PREFACE

This volume contains most of the invited and contributed papers presented at the 5th International Workshop on Beam Injection Assessment of Defects in Semiconductors (BIADS 98), which took place in the Parkhotel Schloss Wulkow near Berlin, Germany, August 30 – September 3, 1998. BIADS 98 focussed on theoretical and experimental topics related to the assessment of microstructures and defects in semiconductors. The purpose was to bring together specialists working in this field in both fundamental research and application. There were more than 80 participants from 15 countries all over the world.

The topics of the BIADS 98 program were: Charge collection microscopy and related methods, Luminescence, Near field methods and STM, Advanced methods and applications, Application of beam injection to technology and to device and heterostructures. The program consisted of 18 invited talks, 16 oral presentations, 34 posters, and a round-table discussion. A summary of the round-table discussion on "The future of beam injection techniques" is also included in this volume. The majority of papers contained in this volume have been reviewed and modified accordingly.

The ten years of BIADS (1988 to 1998) represent a series of meetings which started in Paris (1988, 1991) and continued in Bologna (1993), El Escorial (1996), and Wulkow near Berlin (1998).

The Scientific Committee of BIADS has decided to modify the title of the forthcoming workshop. The new title will be "Beam Injection Assessment of Microstructures in Semiconductors" (BIAMS). This new title reflects the development towards assessment of microstructures, a more general issue, which includes the defects. The next International Workshop BIAMS will be held in autumn 2000 in Japan, i. e. for the first time outside of Europe.

We would like to thank the participants for their high-level contributions and the formal and informal discussions held during the meeting which created a pleasant scientific atmosphere and led to numerous contacts useful for future discussions and cooperation. Finally, we would like to express our gratitude to the people and institutions who supported the workshop, in particular the members of the Local Organising Committee, the Deutsche Forschungsgemeinschaft and the European Commission, through the Euroconference program.

Martin Kittler Otwin Breitenstein Arthur Endrös Wolfgang Schröter

